

STY30NA50

N - CHANNEL ENHANCEMENT MODE FAST POWER MOS TRANSISTOR

PRELIMINARY DATA

TYPE	V _{DSS}	R _{DS(on)}	ΙD
STY30NA50	500 V	< 0.175 Ω	30 A

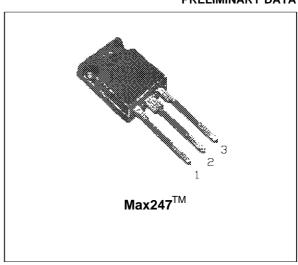
- TYPICAL $R_{DS(on)} = 0.15 \Omega$
- EFFICIENT AND RELIABLE MOUNTING THROUGH CLIP
- ± 30V GATE TO SOURCE VOLTAGE RATING
- REPETITIVE AVALANCHE TESTED
- LOW INTRINSIC CAPACITANCE
- 100% AVALANCHE TESTED
- GATE CHARGE MINIMIZED
- REDUCED THRESHOLD VOLTAGE SPREAD

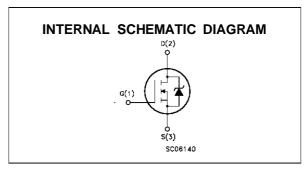
DESCRIPTION

The Max247TM package is a new high volume power package exibiting the same footprint as the industry standard TO-247, but designed to accomodate much larger silicon chips, normally supplied in bigger packages such as TO-264. The increased die capacity makes the device ideal to reduce component count in multiple paralleled designs and save board space with respect to larger packages.

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES (UPS)





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	500	V
V_{DGR}	Drain- gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	500	V
V_{GS}	Gate-source Voltage	± 30	V
I_D	Drain Current (continuous) at T _c = 25 °C	30	Α
ΙD	Drain Current (continuous) at T _c = 100 °C	19	Α
I _{DM} (•)	Drain Current (pulsed)	120	Α
P _{tot}	Total Dissipation at T _c = 25 °C	300	W
	Derating Factor	2.4	W/°C
T_{stg}	Storage Temperature	-55 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

(•) Pulse width limited by safe operating area

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THERMAL DATA

R _{thj-case}	Thermal Resistance Junction-case Thermal Resistance Junction-ambient	Max Max	0.42 40	°C/W °C/W
R _{thc-sink}	Thermal Resistance Case-Heatsink	Тур	0.05	
	with Conductive Grease			

AVALANCHE CHARACTERISTICS

Symbol	Parameter	Max Value	Unit
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max, $\delta < 1\%$)	30	А
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	3000	mJ
E _{AR}	Repetitive Avalanche Energy (pulse width limited by T_j max, δ < 1%)	180	mJ
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive $(T_c = 100 ^{\circ}\text{C}, \text{pulse width limited by } T_j \text{max}, \delta < 1\%)$	19	А

ELECTRICAL CHARACTERISTICS ($T_{case} = 25$ ^{o}C unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	500			<
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating x 0.8 T_c = 125 °C$			200 1000	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 30 V			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250 \mu A$	2.25	3	3.75	V
R _{DS(on)}	Static Drain-source On Resistance	$V_{GS} = 10 \text{ V}$ $I_D = 15 \text{ A}$ $V_{GS} = 10 \text{ V}$ $I_D = 15 \text{ A}$ $T_c = 100^{\circ}\text{C}$		0.15	0.175 0.35	Ω Ω
I _{D(on)}	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 \text{ V}$	30			А

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
gfs (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_{D} = 15 \text{ A}$	25			S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25 V f = 1 MHz V _{GS} = 0		6150 780 220	8000 1000 290	pF pF pF



ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Time Rise Time	$V_{DD} = 250 \text{ V}$ $R_G = 4.7 \Omega$	$I_D = 15 A$ $V_{GS} = 10 V$		40 70	55 90	ns ns
(di/dt) _{on}	Turn-on Current Slope	$V_{DD} = 400 \text{ V}$ $R_G = 47 \Omega$	I _D = 30 A V _{GS} = 10 V		240		A/μs
$egin{array}{c} Q_g \ Q_{gs} \ Q_{gd} \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 400 V I _D =	= 30 A V _{GS} = 10 V		245 27 120	320	nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Co	nditions	Min.	Тур.	Max.	Unit
$t_{r(Voff)}$	Off-voltage Rise Time	V _{DD} = 400 V	$I_D = 30 \text{ A}$		75	100	ns
t _f	Fall Time	$R_G = 4.7 \Omega$	$V_{GS} = 10 \text{ V}$		30	40	ns
tc	Cross-over Time				110	145	ns

SOURCE DRAIN DIODE

Symbol	Parameter	Test C	Min.	Тур.	Max.	Unit	
I _{SD} I _{SDM} (∙)	Source-drain Current Source-drain Current (pulsed)					30 120	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 30 A	V _{GS} = 0			1.6	V
t _{rr}	Reverse Recovery	I _{SD} = 30 A V _{DD} = 100 V	$di/dt = 100 \text{ A/}\mu\text{s}$ $T_i = 150 ^{\circ}\text{C}$		800		ns
Q_{rr}	Reverse Recovery Charge		,		17.6		μC
I_{RRM}	Reverse Recovery Current				44		А

^(*) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 % (•) Pulse width limited by safe operating area

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